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Robust surface structure analysis with reliable uncertainty estimation using the exchange Monte Carlo method. Corrigendum

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An error in the article by Nagai, Anada, Nakanishi-Ohno, Okada & Wakabayashi [*J. Appl. Cryst.* (2020), **53**, 387–392] is corrected.

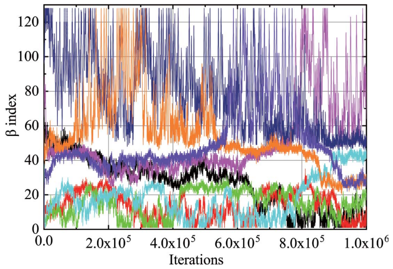
Equation (11) in the article by Nagai *et al.* (2020) should read

$$C_{\rm E}(j) = \frac{\sum_i \Delta(\mathbf{Q}_i)\Delta(\mathbf{Q}_{i+j})}{\sum_i [\Delta(\mathbf{Q}_i)]^2}.$$

The inset of Fig. 6 was calculated with the correct equation, and therefore no change is needed in the rest of the paper.

References

Nagai, K., Anada, M., Nakanishi-Ohno, Y., Okada, M. & Wakabayashi, Y. (2020). *J. Appl. Cryst.* **53**, 387–392.



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